

# Search Notes



Application/Control No.

10/810,324

Examiner

Tien Dinh

Applicant(s)/Patent under Reexamination

HENLEY ET AL.

Art Unit

3644

## SEARCHED

Class	Subclass	Date	Examiner
244	118.5		
	118.6	11/05	JD
297	217.3	11/05	JD
439	110		
	112		
	121	11/05	JD

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Src		11/05	JD
2			
whole			

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Est Text	11/05	JD